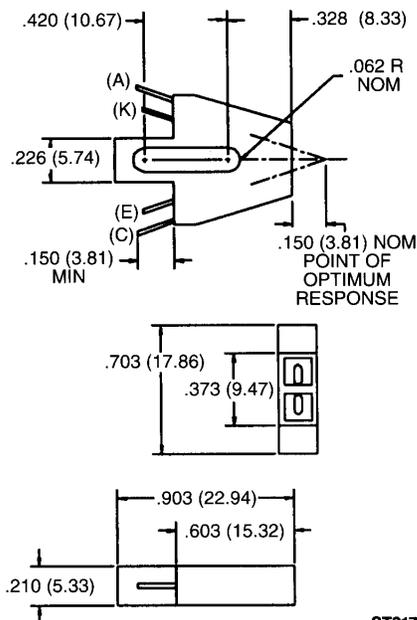


**PACKAGE DIMENSIONS**



ST2178

(C) COLLECTOR  
(E) EMITTER  
(K) CATHODE  
(A) ANODE

NOTES:

1. CATHODE AND EMITTER LEADS ARE .050 NOM SHORTER THAN ANODE AND COLLECTOR LEADS.
2. DIMENSIONS ARE IN INCHES (mm).
3. TOLERANCE IS  $\pm .010"$  [.25] UNLESS OTHERWISE SPECIFIED.

**DESCRIPTION**

The QRC1113 consists of an infrared emitting diode and an NPN silicon phototransistor mounted side by side on a converging optical axis in a black plastic housing. The phototransistor responds to radiation from the emitting diode only when a reflective object passes within its field of view. The area of the optimum response approximates a circle .200" in diameter.

**FEATURES**

- Phototransistor output
- High Sensitivity
- Low cost plastic housing



## REFLECTIVE OBJECT SENSORS

<b>ABSOLUTE MAXIMUM RATINGS</b> ( $T_A = 25^\circ\text{C}$ Unless Otherwise Specified)	
Storage Temperature	-40°C to + 85°C
Operating Temperature	-40°C to + 85°C
Soldering:	
Lead Temperature (Iron)	240°C for 5 sec. <sup>(2,3,4)</sup>
Lead Temperature (Flow)	260°C for 10 sec. <sup>(2,3)</sup>
<b>INPUT DIODE</b>	
Continuous Forward Current	50 mA
Reverse Voltage	5.0 Volts
Power Dissipation	100 mW <sup>(1)</sup>
<b>OUTPUT TRANSISTOR</b>	
Collector-Emitter Voltage	30 Volts
Emitter-Collector Voltage	5.0 Volts
Collector Current	40 mA
Power Dissipation	100 mW <sup>(1)</sup>

<b>ELECTRICAL CHARACTERISTICS</b> ( $T_A = 25^\circ\text{C}$ Unless Otherwise Specified)						
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNITS	TEST CONDITIONS
<b>INPUT DIODE</b>						
Forward Voltage	$V_F$	—		1.70	V	$I_F = 40\text{ mA}$
Reverse Leakage Current	$I_R$	—		100	$\mu\text{A}$	$V_R = 2.0\text{ V}$
<b>OUTPUT TRANSISTOR</b>						
Emitter-Collector Breakdown	$BV_{ECO}$	5		—	V	$I_E = 100\mu\text{A}, E_e = 0$
Collector-Emitter Breakdown	$BV_{CEO}$	30		—	V	$I_C = 1.0\text{ mA}, E_e = 0$
Collector-Emitter Leakage	$I_{CEO}$	—		100	nA	$V_{CE} = 10.0\text{ V}, E_e = 0$
<b>COUPLED</b>						
On-State Collector Current	$I_{C(ON)}$	.200		—	mA	$I_F = 40\text{ mA}, V_{CE} = 5\text{ V}, D = .150^{(5,7)}$
Crosstalk	$I_{CX}$	—		1.0	$\mu\text{A}$	$I_F = 40\text{ mA}, V_{CE} = 5\text{ V}^{(6)}$
Saturation Voltage	$V_{CE(SAT)}$	—		0.40	V	$I_F = 40\text{ mA}, I_C = .1\text{ mA}, D = .150^{(5,7)}$

<b>NOTES</b>
<ol style="list-style-type: none"> <li>1. Derate power dissipation linearly 1.67 mW/°C above 25°C.</li> <li>2. RMA flux is recommended.</li> <li>3. Methanol or Isopropyl alcohols are recommended as cleaning agents.</li> <li>4. Soldering iron 1/16" (1.6mm) from housing.</li> <li>5. D is the distance from the assembly face to the reflective surface.</li> <li>6. Cross talk is the photocurrent measured with current to the input diode and no reflecting surface.</li> <li>7. Measured using Eastman Kodak neutral test card with 90% diffused reflecting surface.</li> </ol>